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Patent Number(s): JP2012122830-A

Title: Physical-property measuring apparatus has several terahertz wave detection elements to which probe lights are irradiated at different delay times

Inventor Name(s): KOMATSU K

Patent Assignee(s): HITACHI NAKA ELECTRONICS KK (HITA-Non-standard)

Derwent Primary Accession No.: 2012-H51185

Abstract: NOVELTY - The apparatus has femtosecond laser (1) divided into pump light (3) and probe lights (4a-4d), in which pump light is radiated to terahertz wave generation element (6). The terahertz wave from element (6) is irradiated towards sample (9), when probe lights are irradiated to terahertz wave detection elements (10a-10d). The waves reflected from sample are received and converted into electric signal synchronized with probe lights, to measure physical property sample. The irradiation probe lights towards detection elements are delayed by different delay times.

USE - Physical-property measuring apparatus.

ADVANTAGE - The physical property the sample can be measured accurately, without using large-sized femtosecond laser. The cost the physical-property measuring apparatus can be reduced.

DESCRIPTION DRAWING(S) - The drawing shows a schematic view the physical-property measuring apparatus.

Femtosecond laser (1)

Pump light (3)

Probe lights (4a-4d)

Terahertz wave generation element (6)

Sample (9)

Terahertz wave detection elements (10a-10d)

Drawing:

Derwent Class Code(s): S03 (Scientific Instrumentation, photometry, calorimetry)

Derwent Manual Code(s): S03-E04A5

IPC: G01N-021/35

Patent Details:

Patent Number	Publ. Date	Main IPC	Week	Page Count	Language
JP2012122830-A	28 Jun 2012	G01N-021/35	201243	Pages: 7	Japanese

Application Details and Date:

JP2012122830-A JP273371 08 Dec 2010

Priority Application Information and Date:

JP273371 08 Dec 2010